



Environmental Analysis Associates, Inc.

A new universal Optical and SEM Air-O-Cell analysis method.

Finding one sampling media capable of performing both Optical and Electron Microscopy on the exact same particles without complicated sample preparation has always been the elusive "holy grail" of particle analysis

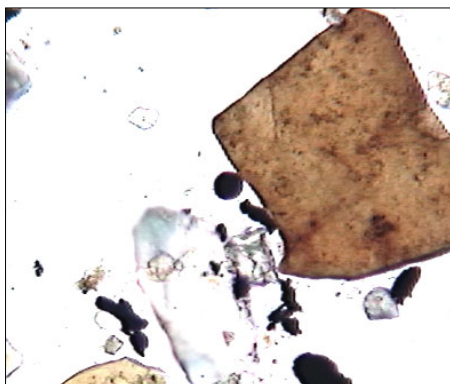
New Slit Impaction Media Capabilities :

- Extended sampling temperature range (0° – 150°F)
- Lower d_{50} cut point (1.5 μ m)
- Examination by both Optical and Electron Microscopy
- High chemical media stability / alcohol resistant
- Rapid preparation and analysis techniques for Electron Microscopy
- High electron beam stability
- Low X-ray background allows quantitative elemental analysis

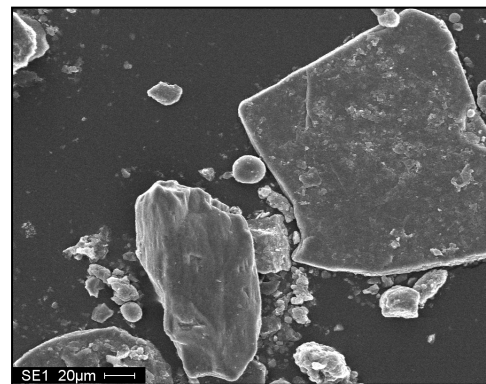


Universal Microscopy Analysis

The new proprietary adhesive provides superior optical clarity and chemical resistance allowing biological staining and optical analysis and then extraction and re-analysis of the exact same particles by electron microscopy.



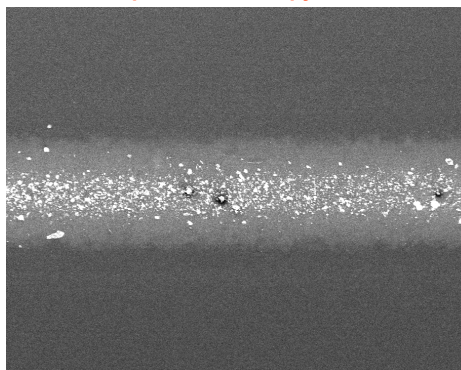
Optical microscopy ~400x



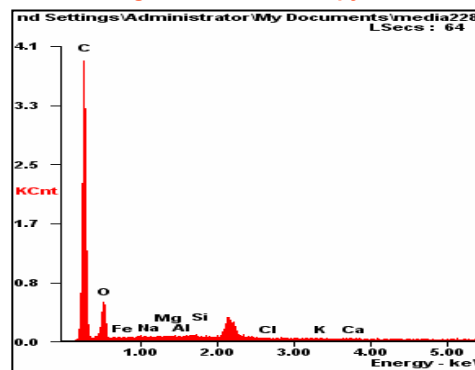
Scanning Electron Microscopy ~400x

Superior Electron Beam Analysis Properties

The smooth background allows for high contrast particle imaging, high beam stability, and low X-ray background (Carbon & Oxygen only). Note: The unlabeled peak is the gold coating applied to enhance sample conductivity.



Example deposition trace (SEM) ~40x



Background X-ray spectrum of the new media

For more information, please contact me at 858-272-7747.

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